

Notice of References Cited	Application/Control No. 09/751,288		Applicant(s)/Patent Under Reexamination STEFANIK, JOHN R.	
	Examiner ANNAN Q. SHANG		Art Unit 2424	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,104,334	08-2000	Allport, David E.	341/175
*	B	US-6,346,891	02-2002	Feinleib et al.	340/825.69
*	C	US-6,812,881	11-2004	Mullaly et al.	341/176
*	D	US-2002/0059597	05-2002	Kikinis et al.	725/39
*	E	US-6,484,011	11-2002	Thompson et al.	455/3.06
*	F	US-6,509,908	01-2003	Croy et al.	715/716
*	G	US-6,388,715	05-2002	Eggen et al.	348/569
*	H	US-6,313,887	11-2001	Gudorf, Gregory D.	348/734
*	I	US-6,804,357	10-2004	Ikonen et al.	380/241
*	J	US-6,108,271	08-2000	Junkin, William F.	367/127
*	K	US-6,069,672	05-2000	Claassen, Henning J.	348/734
*	L	US-5,554,980	09-1996	Hashimoto et al.	340/825.72
*	M	US-5,977,964	11-1999	Williams et al.	715/721

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.